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RF Exposure Evaluation Report

Product : ESP-01M

Trade mark : N/A

Model/Type reference : ESP-01M

Serial Number : N/A

Report Number : EED32J00203502 **FCC ID** : 2AHMR-ESP01M

Date of Issue : Sep. 28, 2017

47 CFR Part 1.1307

Test Standards : 47 CFR Part 1.1310

KDB 447498 D01v06

Test result : PASS

Prepared for:

Shenzhen Ai-Thinker Technology Co., LTD 6/F, Block C2, Huafeng Industrial Park, Hangcheng Road, Baoan district, Shenzhen, China

Prepared by:

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Date:

Sep. 28, 2017

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2 Version

Version No.	Date	- 1	Description	
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4 General Information

4.1 Client Information

Applicant:	Shenzhen Ai-Thinker Technology Co., LTD		
Address of Applicant: 6/F, Block C2, Huafeng Industrial Park, Hangcheng Road, Baoan distri Shenzhen, China			
Manufacturer: Shenzhen Ai-Thinker Technology Co., LTD			
Address of Manufacturer: 6/F, Block C2, Huafeng Industrial Park, Hangcheng Road, Bac Shenzhen, China			
Factory:	Shenzhen Ai-Thinker Technology Co., LTD		
Address of Factory:	6/F, Block C2, Huafeng Industrial Park, Hangcheng Road, Baoan district, Shenzhen, China		

4.2 General Description of EUT

Product Name:	ESP-01M
Model No.:	ESP-01M
Trade Mark:	N/A
EUT Supports Radios application:	Wi-Fi: 802.11 b/g/n(20M) , 2412MHz-2462MHz
Power Supply:	DC 3.3V

4.3 Product Specification subjective to this standard

Modulation Type:	DSSS, OFDM		
Antenna Type:	PCB Antenna		
Antenna Gain:	3dBi		
Test Voltage:	DC 3.3V	6	6.
Sample Received Date:	Sep. 12, 2017		
Sample tested Date:	Sep. 12, 2017 to Sep. 28, 2017		
The tested sample and the	e sample information are provided I	by the client.	

4.4 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd.

Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China 518101

Telephone: +86 (0) 755 3368 3668 Fax:+86 (0) 755 3368 3385

No tests were sub-contracted.















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4.5 Deviation from Standards

None.



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4.6 Abnormalities from Standard Conditions

None.



None.

















































































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5 RF Exposure Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Limits

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in part1.1307(b)

TABLE 1-LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)	
(A) Lim	its for Occupational	/Controlled Exposure	es		
0.3–3.0 3.0–30 30–300 300–1500 1500–100,000	614 1842/f 61.4	1.63 4.89/f 0.163	*(100) *(900/f²) 1.0 f/300 5	6 6 6 6	
(B) Limits	for General Populati	on/Uncontrolled Exp	osure		
0.3–1.34 1.34–30 30–300 300–1500 1500–100,000	614 824/f 27.5	1.63 2.19/f 0.073	*(100) *(180/f²) 0.2 f/1500 1.0	30 30 30 30 30	

A rough estimation of the expected exposure in power flux density on a given point can be made with the following equation:

$$S = \frac{P \times G}{4 \times \pi \times R^2}$$

Where:

S = power density

P = power input to the antenna

G = numeric gain of the antenna in the direction of interest relative to an isotropic radiator

R= distance to the centre of radiation of the antenna

EIRP = P*G

The antenna of the product, under normal use condition is at least 20 cm away from the body of the user. Warning statement to the user for keeping at least 20cm separation distance and the prohibition of operating to a person has been printed on the user's manual. Therefore, the S of the device is calculated with R=20cm, and if it is below the limits, then we can conclude the device complies with the rules.

5.1.2 Test Procedure

Software provided by client enabled the EUT to transmit data at lowest, middle and highest channel individually.



















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5.1.3 EUT RF Exposure Evaluation

Antenna Gain: 3dBi

Output Power Into Antenna & RF Exposure Evaluation Distance:

Channel	Frequency (MHz)	Max Conducted Peak Output Power(dBm)	Gain (dBi)	EIRP* (dBm)	EIRP (mW)	R (cm)	S (mW/cm ²)	Limit (mW/cm²)	Result
Lowest	2412	16.99	3	19.99	99.77	20	0.020	1.0	Pass











































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PHOTOGRAPHS OF EUT Constructional Details

Refer to Report No. EED32J00203501 for EUT external and internal photos.

*** End of Report ***

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